


<b>Search Notes</b>  	<b>Application/Control No.</b>  10656846	<b>Applicant(s)/Patent Under Reexamination</b>  CHU ET AL.
	<b>Examiner</b>  SIMON KE	<b>Art Unit</b>  2174

SEARCHED			
Class	Subclass	Date	Examiner
715	780, 781	1/22/08	PK
715	780, 781	7/6/08	PK
715	780, 781, 501, 513, 84-843, 790, 797, 853-855 and 760	1/4/09	PK
715	780, 781, 501, 513, 84-843, 790, 797, 853-855 and 760	7/17/09	PK

SEARCH NOTES		
Search Notes	Date	Examiner
East Text Search (715/501, 513, 84-843, 790, 797, 781, 853-855 and 760 USPAT; US PUB; EPO; JPO; DERWENT)	1/22/08	PK
East Text Search (715/501, 513, 84-843, 790, 797, 781, 853-855 and 760 USPAT; US PUB; EPO; JPO; DERWENT)	7/6/08	PK
East Text Search (715/501, 513, 84-843, 790, 797, 781, 853-855 and 760 USPAT; US PUB; EPO; JPO; DERWENT)	1/4/09	PK
East Text Search (715/501, 513, 84-843, 790, 797, 781, 853-855 and 760 USPAT; US PUB; EPO; JPO; DERWENT)	7/17/09	PK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--